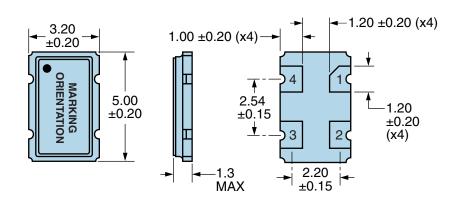


| LLLCTRICAL SFLUIFICA | |
|-----------------------------------|---|
| Nominal Frequency | 6.451MHz |
| Frequency Tolerance/Stability | ±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, 1st Year Aging at 25 °C, Shock, and Vibration) |
| Aging at 25°C | ±5ppm/year Maximum |
| Operating Temperature Range | -20°C to +70°C |
| Supply Voltage | 5.0Vdc ±10% |
| Input Current | 45mA Maximum (Unloaded) |
| Output Voltage Logic High (Voh) | Vdd-0.4Vdc Minimum (IOH = -16mA) |
| Output Voltage Logic Low (Vol) | 0.4Vdc Maximum (IOH = +16mA) |
| Rise/Fall Time | 4nSec Maximum (Measured at 20% to 80% of waveform) |
| Duty Cycle | 50 \pm 10(%) (Measured at 1.4Vdc with TTL Load, or at 50% of waveform with HCMOS Load) |
| Load Drive Capability | 50pF HCMOS Load Maximum |
| Output Logic Type | CMOS |
| Pin 1 Connection | Power Down (Disabled Output: Logic Low) |
| Pin 1 Input Voltage (Vih and Vil) | +2.0Vdc Minimum to enable output, +0.8Vdc Maximum to disable output, No Connect to enable output. |
| Standby Current | 50μA Maximum (Pin 1 = Ground) |
| Disable Current | 30mA Maximum (Pin 1 = Ground) |
| Absolute Clock Jitter | ±250pSec Maximum, ±100pSec Typical |
| One Sigma Clock Period Jitter | ±50pSec Maximum |
| Start Up Time | 10mSec Maximum |
| Storage Temperature Range | -55°C to +125°C |
| | |

| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS | |
|---|---------------------------------------|
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C |
| Mechanical Shock | MIL-STD-202, Method 213, Condition C |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 |
| Resistance to Solvents | MIL-STD-202, Method 215 |
| Solderability | MIL-STD-883, Method 2003 |
| Temperature Cycling | MIL-STD-883, MEthod 1010 |
| Vibration | MIL-STD-883, Method 2007, Condition A |

MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|------|---------------------------------|
| 1 | Power Down (Logic Low) |
| 2 | Ground/Case Ground |
| 3 | Output |
| 4 | Supply Voltage |
| LINE | MARKING |
| 1 | E6.451 E=Ecliptek Designator |

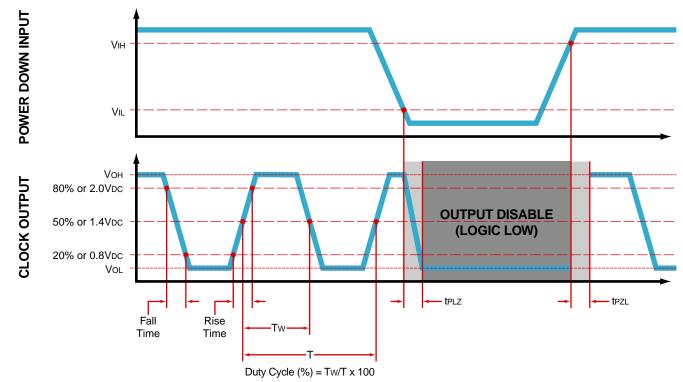
Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1

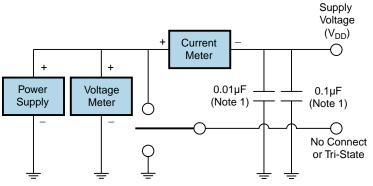


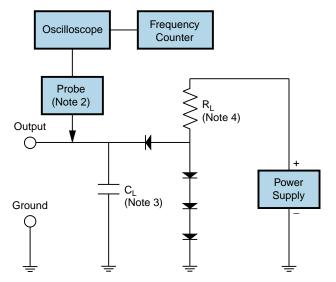


Test Circuit for TTL Output

| Output Load Drive Capability | R _L Value (Ohms) | C _L Value (pF) |
|---------------------------------|--------------------------------|------------------------------|
| 10TTL | 390 | 15 |
| 5TTL | 780 | 15 |
| 2TTL | 1100 | 6 |
| 10LSTTL | 2000 | 15 |
| 1TTL | 2200 | 3 |







Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth

(>300MHz) passive probe is recommended.

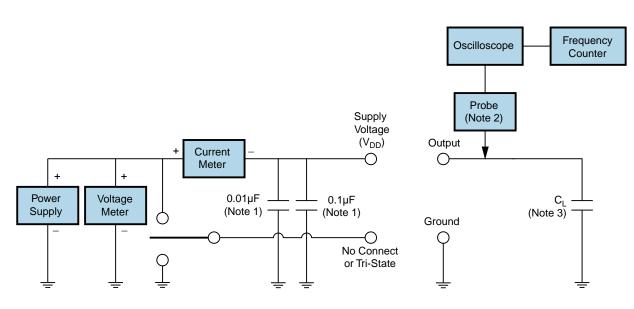
Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

Note 4: Resistance value R_L is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.

Note 5: All diodes are MMBD7000, MMBD914, or equivalent.



Test Circuit for CMOS Output



Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

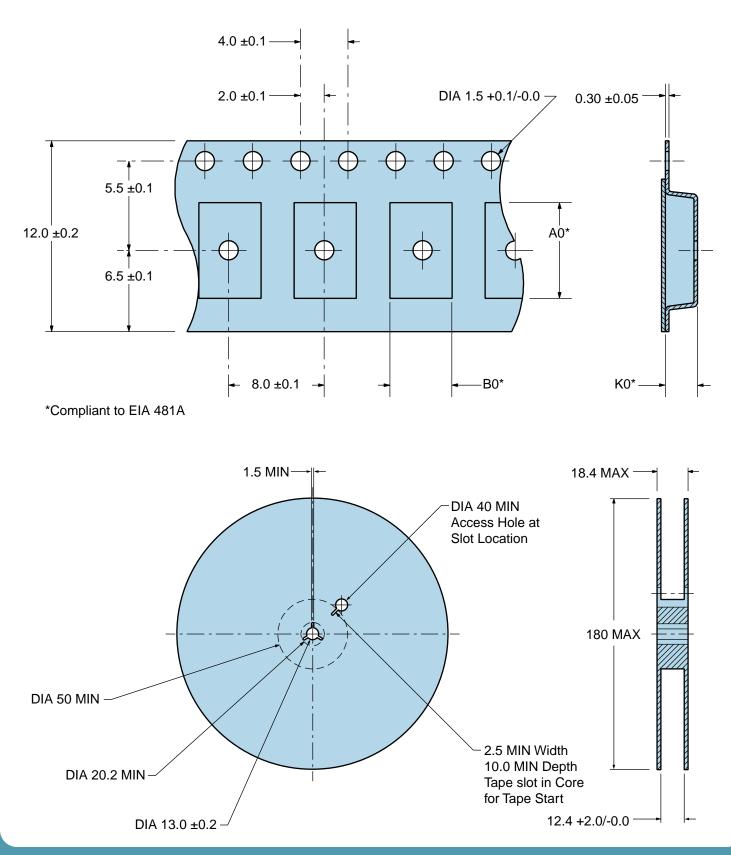
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_1 includes sum of all probe and fixture capacitance.



Tape & Reel Dimensions

Quantity Per Reel: 1,000 units

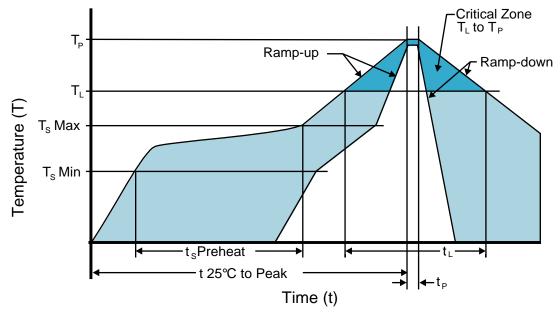


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Recommended Solder Reflow Methods

EP3545PDC-6.451M TR



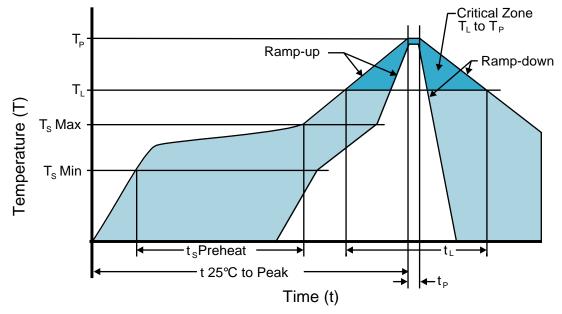
High Temperature Infrared/Convection

| · · | |
|---|--------------------------------------|
| T_s MAX to T_L (Ramp-up Rate) | 3°C/second Maximum |
| Preheat | |
| - Temperature Minimum (T _s MIN) | 150°C |
| - Temperature Typical (T _s TYP) | 175°C |
| Temperature Maximum (T_s MAX) | 200°C |
| - Time (t _s MIN) | 60 - 180 Seconds |
| Ramp-up Rate (T⊾ to T _P) | 3°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T∟) | 217°C |
| - Time (t∟) | 60 - 150 Seconds |
| Peak Temperature (T _P) | 260°C Maximum for 10 Seconds Maximum |
| Target Peak Temperature (T _P Target) | 250°C +0/-5°C |
| Time within 5°C of actual peak (t _p) | 20 - 40 seconds |
| Ramp-down Rate | 6°C/second Maximum |
| Time 25°C to Peak Temperature (t) | 8 minutes Maximum |
| Moisture Sensitivity Level | Level 1 |
| | |



Recommended Solder Reflow Methods

EP3545PDC-6.451M TR



Low Temperature Infrared/Convection 240°C

| T _s MAX to T _L (Ramp-up Rate) | 5°C/second Maximum | |
|---|--|--|
| Preheat | | |
| - Temperature Minimum (Ts MIN) | N/A | |
| - Temperature Typical (T _s TYP) | 150°C | |
| - Temperature Maximum (T _s MAX) | N/A | |
| - Time (t _s MIN) | 60 - 120 Seconds | |
| Ramp-up Rate (T⊾ to T _P) | 5°C/second Maximum | |
| Time Maintained Above: | | |
| - Temperature (T∟) | 150°C | |
| - Time (t∟) | 200 Seconds Maximum | |
| Peak Temperature (T _P) | 240°C Maximum | |
| Target Peak Temperature (T _P Target) | 240°C Maximum 1 Time / 230°C Maximum 2 Times | |
| Time within 5°C of actual peak (t _p) | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time | |
| Ramp-down Rate | 5°C/second Maximum | |
| Time 25°C to Peak Temperature (t) | N/A | |
| Moisture Sensitivity Level | Level 1 | |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.